

[METHOD FOR DESIGNING AN INTEGRATED CIRCUIT DEFECT MONITOR]

Abstract

A method and system for designing a test structure. The method including: defining and placing test circuit pins in an integrated circuit design; routing one or more fat wires, each fat wire routed between a set of the test circuit pins; processing each fat wire into a continuous wire and one or more corresponding wire segments adjacent to the continuous wire, the continuous wire separated from the one or more corresponding wire segments by a space; and connecting the continuous wire and the one or more wire segments to circuit elements of a defect monitor scan chain, the circuit elements previously inserted into the integrated circuit design.